

<b>Notice of References Cited</b>	Application/Control No. 10/817,200	Applicant(s)/Patent Under Reexamination AMRHEIN ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,907,534	03-1990	Huang et al.	118/725
*	B	US-5,370,738	12-1994	Watanabe et al.	118/725
*	C	US-5,525,157	06-1996	Hawkins et al.	118/715
*	D	US-5,807,614	09-1998	Sindzingre et al.	427/540
*	E	US-5,916,369	06-1999	Anderson et al.	118/715
*	F	US-6,110,556	08-2000	Bang et al.	428/64.1
*	G	US-6,203,657 B1	03-2001	Collison et al.	156/345.48
*	H	US-6,450,116 B1	09-2002	Noble et al.	118/723R
*	I	US-6,450,117 B1	09-2002	Muruges h et al.	118/723ME
*	J	US-2001/0023741 A1	09-2001	Collison et al.	156/345
*	K	US-2002/0011210 A1	01-2002	Satoh et al.	118/715
*	L	US-2004/0149223 A1	08-2004	Collison et al.	118/723.01R
*	M	US-2007/0062646 A1	03-2007	Ogawa et al.	156/345.29

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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